

**Notice of References Cited**

Application/Control No.

09/657,532

Applicant(s)/Patent Under

Reexamination

ANDRADE ET AL.

Examiner

Po-Wei (Dennis) Chen

Art Unit

2676

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,788,588	11-1988	Tomita, Hideo	348/602
	B	US-5,489,918	02-1996	Mosier, Donald E.	345/89
	C	US-6,624,828	09-2003	Dresevic et al.	345/771
	D	US-6,094,185	07-2000	Shirriff, Kenneth W.	345/102
	E	US-6,400,374	06-2002	Lanier, Jaron	345/630
	F	US-6,496,170	12-2002	Yoshida et al.	345/87
	G	US-6,345,111	02-2002	Yamaguchi et al.	382/118
	H	US-5,410,609	04-1995	Kado et al.	382/118
	I	US-6,002,386	12-1999	Gu, Sung-Jin	345/690
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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